

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
		scan \$3 same movement same detector same input adj image	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 10:23
		358/509.ccls.	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:28
		(projecting adj image) same (sensing with detector)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:29
		projecting adj image same (sensing with detector)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:28
		projecting adj image same (sensing with detector)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:54
L1	1595	relative adj scan\$3	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 12:48
L2	0	relative adj scan\$3 adj movement same detector	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 12:48
L3	73	relative adj scan\$4 same detector with image	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 12:49
S1	15373	(project\$3 with image) same (feature mark defect scratch deposit)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:55
S2	31	(project\$3 with image) same (feature mark defect scratch deposit) same (deduc\$3)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/05 09:10
S3	891	(project\$3 with image) same (feature mark defect scratch deposit) same detector	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/05 09:11

S4	2	(project\$3 with image) same (feature mark defect scratch deposit) same detector same deduc\$3	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/05 09:13
S5	33	(project\$3 with image) same (feature mark defect scratch deposit) same detector same(analyz\$3 deduc\$3 conceiv\$3 deduct\$3)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/05 09:17
S6	11	(project\$3 with image) with (feature mark defect scratch deposit) same detector same(analyz\$3 deduc\$3 conceiv\$3 deduct\$3)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/05 10:23
S10	1057	(image adj project\$4) with (feature mark scratch defect deposit)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:54
S11	29	(image adj project\$4) with (feature mark scratch defect deposit) with detector	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/05 10:54
S12	869	project\$3 with image same (sens\$3 with detector)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/05 10:55
S13	869	(project\$3 with image) same (sens\$3 with detector)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/05 10:57
S14	4	(project\$3 with image) same (sens\$3 with detector) and (deduc\$3 with location)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/05 11:01
S15	15	(project\$3 with image) and (sens\$3 with detector) and (deduc\$3 with location)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/05 12:22
S16	14	projecting adj image same (sensing with detector)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/10 13:27
S17	14	projecting adj image same (sensing with detector)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/10 13:26
S18	238	358/509.ccls	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/10 13:27

S19	0	358/509.ccls. and S16	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/10 13:27
S20	1	projecting adj image same (sensing with detector) and "358"/\$.ccls.	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/10 14:34
S21	2	"5153745".pn.	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/10 14:52
S22	0	"09401574"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/10 15:19
S23	1	(monitoring adj color) same (scanline) and "358"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/10 15:19
S24	1	("2002/0093694"):URPN.	USPAT	OR	OFF	2004/05/10 15:20
S25	0	color with illumination same scanline and "358"/\$.ccls.	USPAT	OR	OFF	2004/05/10 15:21
S26	1	((color colour) with illumination) same scanline	USPAT	OR	OFF	2004/05/10 15:21
S27	2	((color colour) with illumination) same scanline	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/10 15:22
S28	920	((color colour) with illumination) same length	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/10 15:22
S29	5	monitor\$3 with ((color colour) with illumination) same length	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/10 15:24
S30	103	((color colour) with illumination) same length same scan\$4	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/10 15:47
S31	20689	measur\$3 with time with T	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/10 15:48
S32	476	measur\$3 with time with T with intensity	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/10 15:48

S33	7	measur\$3 with time with T with intensity same (pel pixel pixle)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/10 15:49
S34	202	measur\$3 with time with T with intensity same (lamp light pel pixel pixle)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/10 15:50
S35	13	measur\$3 with time with T with intensity same (lamp light) and (pel pixel pixle)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/10 15:50
S36	2	measur\$3 with time with T with intensity same ((lamp light) and (pel pixel pixle))	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/10 15:53
S37	0	measur\$3 with time with T with intensity same (pel pixel pixle) with scanline	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/10 15:54
S38	47	intensity same (pel pixel pixle) with scanline	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/10 15:56
S39	28	intensity with lamp same position same (pel pixel pixle)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 08:44
S40	1	(pel pixel pixle) with (scan adj line or scanline) same (thermal adj noise)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 08:56
S41	0	(pel pixel pixle) with (scan adj line or scanline) same (thermal adj noise) same intensity	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 08:45
S42	0	"55843400".pn.	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 08:48
S43	2	"5584340".pn.	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 08:48
S44	0	(pel pixel pixle) with (scan adj line or scanline) and (thermal adj noise) with intensity	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 09:00

S45	1	(pel pixel pixle) with (scan adj line or scanline) and (thermal adj noise) same intensity	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 09:06
S46	94	(pel pixel pixle) and (scan adj line or scanline) and (thermal adj noise) and intensity	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:27
S47	33	(pel pixel pixle) and (scan adj line or scanline) and (thermal adj noise) and intensity and "358"/	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 09:08
S48	8	(pel pixel pixle) and (scan adj line or scanline) and (thermal adj noise) and intensity and "358"/% ccls	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 09:16
S49	2	storing with (imag\$3 adj array) and scanline	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 09:17
S50	3	interpolat\$3 adj intensity same illumination	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 09:19
S51	20	interpolat\$3 adj intensity same array	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 09:20
S52	1	interpolat\$3 adj intensity same scanline	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 09:26
S53	12	output with array with scanline	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 09:27
S54	6	output with array with scanline same (stor\$3 memory)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 09:42
S55	7	output with array with scanline same (stor\$3 memory buffer)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 09:42
S56	7	output with array with scanline same (stor\$3 memory buffer ram rom)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:04

S57	0	output with array with scanline and modify\$3 with (stor\$3 memory buffer ram rom)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:05
S58	14	array with scanline and modify\$3 with (stor\$3 memory buffer ram rom)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:05
S59	1	comput\$3 adj interpolat\$3 adj intensity	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:26
S60	11	comput\$3 with interpolat\$3 adj intensity	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:27
S61	3991	250/208.1	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:27
S62	0	250/208.1 and S50	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:27
S63	0	(pel pixel pixle) and (scan adj line or scanline) and (thermal adj noise) and intensity and 358/480	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:27
S64	0	(pel pixel pixle) and (scan adj line or scanline) and (thermal adj noise) and intensity and 358/475	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:27
S65	0	(projecting adj image) same (sensing with detector) and 358/475	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:28
S66	0	(projecting adj image) same (sensing with detector) and 358/461	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:28
S67	0	projecting adj image same (sensing with detector) and 355/203.ccls.	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:28
S68	0	projecting adj image same (sensing with detector) and 355/228.ccls.	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:28

S69	0	projecting adj image same (sensing with detector) and 355/208.ccls.	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:28
S70	240	358/509.ccls.	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:28
S71	0	(projecting adj image) same (sensing with detector) and 345/606.ccls.	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:29
S72	116	345/643.ccls.	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:29
S73	34	345/643.ccls. and intensity	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:29
S74	0	340/728.ccls. and S60	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:30
S75	0	340/747.ccls.	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:30
S76	0	340/728.ccls.	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:30
S77	0	355/203.ccls.	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:30
S78	311	355/228	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:30
S79	2051	355/208	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:30
S80	213	345/606	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:31

S81	154	345/643	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:31
S82	4108	364/521	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:31
S83	73	364/521 and interpolat\$3 with intensity	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:31
S84	0	364/521 and interpolat\$3 with intensity same scanline	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:32
S85	166	first and second adj measurement and intensity same illumination	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:33
S86	87	first with second adj measurement and intensity same illumination	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:33
S87	67	first with second adj measurement and intensity same illumination and (stor\$3 memory buffer)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:38
S88	121	(first with second) adj (value measurement) and intensity same illumination and (stor\$3 memory buffer)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:41
S89	7	(first with second) adj (value measurement) same intensity same illumination and (stor\$3 memory buffer)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 10:41
S90	0	projecting adj image same (sensing with detector) and 395/117	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:54
S91	4	(image adj project\$4) with (feature mark scratch defect deposit) and 348/189	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:54
S92	8	(image adj project\$4) with (feature mark scratch defect deposit) and 348/781	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:54

S93	4	(image adj project\$4) with (feature mark scratch defect deposit) and 382/149	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:55
S94	7	(image adj project\$4) with (feature mark scratch defect deposit) and 382/151	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:55
S95	1	(image adj project\$4) with (feature mark scratch defect deposit) and 382/217	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:55
S96	4	(image adj project\$4) with (feature mark scratch defect deposit) and 382/275	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:55
S97	4	(image adj project\$4) with (feature mark scratch defect deposit) and 382/287	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:55
S98	7	(image adj project\$4) with (feature mark scratch defect deposit) and 382/291	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:55
S99	10	(project\$3 with image) same (feature mark defect scratch deposit) and 356/3.1	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:56
S100	0	(project\$3 with image) same (feature mark defect scratch deposit) and 356/4.06	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:56
S101	0	(project\$3 with image) same (feature mark defect scratch deposit) and 356/4.06	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:56
S102	1	(project\$3 with image) same (feature mark defect scratch deposit) and 356/309	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:56
S103	6	(project\$3 with image) same (feature mark defect scratch deposit) and 356/319	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:56
S104	1	(project\$3 with image) same (feature mark defect scratch deposit) and 356/320	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:56

S105	0	(project\$3 with image) same (feature mark defect scratch deposit) and 356/322	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:56
S106	2	(project\$3 with image) same (feature mark defect scratch deposit) and 356/484	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:56
S107	30	(project\$3 with image) same (feature mark defect scratch deposit) and 356/121	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:57
S108	14	(project\$3 with image) same (feature mark defect scratch deposit) and 356/123	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:57
S109	20	(project\$3 with image) same (feature mark defect scratch deposit) and 356/614	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:57
S110	13	(project\$3 with image) same (feature mark defect scratch deposit) and 356/620	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:57
S111	11	(project\$3 with image) same (feature mark defect scratch deposit) and 356/622	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:57
S112	0	S111 and S110 and S109 and S108 and S107 and S106 and S104 and S103 and S102 and S99 and S98 and S97 and S95 and S94 and S93 and S92 and S91	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/11 14:58
S113	127	S111 S110 S109 S108 S107 S106 S104 S103 S102 S99 S98 S97 S95 S94 S93 S92 S91	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 09:15
S114	992	deduc\$3 with location	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 09:15
S115	178	deduc\$3 adj2 location	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 09:16
S116	32	deduc\$3 adj2 location and projection	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 09:16

S117	26	deduc\$3 adj2 location and projection and detect\$3	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 10:01
S118	2586	location same projection same detect\$3	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 10:04
S119	502	location same projection same detect\$3 same (feature scratch mark defect)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 10:07
S120	518	location same projection same detect\$3 same (feature scratch mark defect deposit)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 10:11
S121	80	location with projection with detect\$3 same (feature scratch mark defect deposit)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 10:12
S122	64	location with projection with detect\$3 with (feature scratch mark defect deposit)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 10:12
S123	2	location same second adj projection with detect\$3 with (feature scratch mark defect deposit)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 10:12
S124	2	location same (second adj projection) with detect\$3 with (feature scratch mark defect deposit)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 10:41
S125	1	location same (second adj projection) with detect\$3 with (feature scratch mark defect deposit) and len	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 10:41
S126	1	location same (second adj projection) with detect\$3 with (feature scratch mark defect deposit) and lens	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 10:45
S127	2	location same (second adj projection) same detect\$3 same (feature scratch mark defect deposit) same lens	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 10:45
S128	10	(position location) same (second adj projection) same detect\$3 same (feature scratch mark defect deposit) same lens	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 10:50

S129	4278	detector with array same position with array	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 10:51
S130	1312	detector with array same position with image	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 10:51
S131	11	detector with array same position with image near (feature defect scratch deposit mark)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 10:55
S132	1186	mov\$3 with lens same (second adj position)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 10:56
S133	334	mov\$3 with lens same (second adj position) same project\$3	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 10:56
S134	87	mov\$3 with lens with (second adj position) with (projection projected)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 10:57
S135	1	mov\$3 with lens with (second adj position) with (projection projected) and "358"/\$.ccls.	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 10:57
S136	0	"466298".pn.	USPAT	OR	OFF	2004/05/12 10:59
S137	6	"466298".pn.	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 10:59
S138	2	"4666298".pn.	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 13:42
S139	292	illuminat\$4 with (substrate transparent) same (original sheet paper manuscript) same radiation	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/12 13:43
S140	5	illuminat\$4 with (substrate transparent) same (original sheet paper manuscript) same radiation with detector	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 08:39

S141	0	input adj image with correct43 with (feature mark defect deposit scratch)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 08:42
S142	0	electronic with image with correct43 with (feature mark defect deposit scratch)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 08:42
S143	198	electronic with image with correct\$3 same(feature mark defect deposit scratch)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 08:42
S144	115	electronic with image with correct\$3 with(feature mark defect deposit scratch)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 08:42
S145	1	electronic with input adj image with correct\$3 with(feature mark defect deposit scratch)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 08:53
S146	4	electronic same input adj image with correct\$3 with(feature mark defect deposit scratch)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 09:00
S147	18072	(location position)same correct\$3 with(feature mark defect deposit scratch)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 09:00
S148	10240	(location position) with correct\$3 with(feature mark defect deposit scratch)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 09:01
S149	16	(location position) with correct\$3 with(feature mark defect deposit scratch) with input adj image	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 09:03
S150	388	(location position) with correct\$3 with(feature mark defect deposit scratch) with image same (optic\$2 mirror lens)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 09:04
S151	277	(location position) with correct\$3 with(feature mark defect deposit scratch) with image with (optic\$2 mirror lens)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 09:04
S152	160	(location position) with correct\$3 with(feature mark defect deposit scratch) with image near5 (optic\$2 mirror lens)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 09:04

S153	17	(location position) with correct\$3 near (feature mark defect deposit scratch) with image near5 (optic\$2 mirror lens)	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 10:02
S154	1	scanning with movement with detector with input adj image	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 10:03
S155	1	scanning adj movement same detector with input adj image	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 10:03
S156	2	scanning adj movement same detector same input adj image	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 10:04
S157	7	scan\$3 same movement same detector same input adj image	USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/05/13 12:44